

MS 1320 Truman Michelson notes on anthropometric measurements of Beothuk skulls

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Collection Overview

Repository: National Anthropological Archives

Title: MS 1320 Truman Michelson notes on anthropometric measurements of

Beothuk skulls

Date: 1923

Identifier: NAA.MS1320

Creator: Michelson, Truman, 1879-1938

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of Beothuk skulls

Image(s): MS 1320 Truman Michelson notes on anthropometric

measurements of Beothuk skulls

Administrative Information

Available Formats

Digital surrogates are available online.

Citation

Manuscript 1320, National Anthropological Archives, Smithsonian Institution

Scope and Contents

According to Explorations and Field Work of the Smithsonian Institution in 1923 (Pub. 2752), Truman Michelson travelled to St. John's in Newfoundland and Labrador in June 1923 where he made cranial measurements of four Beothuk skulls. These undated notes, most likely from that work, consist of Michelson's measurements of the skulls of a Beothuk child, two adult males, and an adult female.

Local Numbers

NAA MS 1320

Local Note

Title updated from "Physical anthropology of Newfoundland" 4/3/2014.

Names and Subject Terms

This collection is indexed in the online catalog of the Smithsonian Institution under the following terms:

Subjects:

Beothuk Indians Indians of North America -- Subarctic Indians of North America -- anthropometry Physical anthropology

Cultures:

Beothuk Indians Indians of North America -- Subarctic

Types of Materials:

Notes